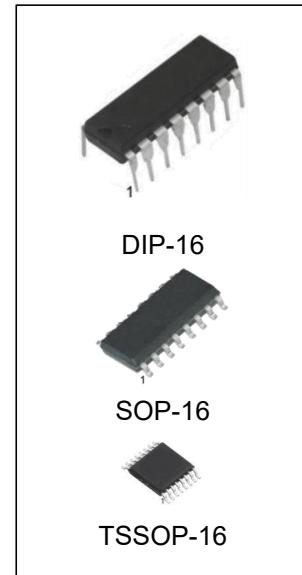


8-stage Shift-and-store Bus Register

Features:

- Wide supply voltage range from 3V to 15V
- Fully static operation
- 5V, 10V, and 15V parametric ratings
- Standardized symmetrical output characteristics
- Specified from -40°C to +125°C
- Packaging information: DIP16/SOP16/TSSOP16



Ordering Information

DEVICE	Package Type	MARKING	Packing	Packing Qty
CD4094BE/ CD4094BN	DIP-16	CD4094B	TUBE	1000pcs/box
CD4094BM/TR	SOP-16	CD4094B	REEL	2500pcs/reel
CD4094BMT/TR	TSSOP-16	CD4094B	REEL	2500pcs/reel

General Description

The CD4094B is an 8-stage serial shift register. It has a storage latch associated with each stage for strobing data from the serial input to parallel buffered 3-state outputs QP0 to QP7. The parallel outputs may be connected directly to common bus lines. Data is shifted on positive-going clock transitions. The data in each shift register stage is transferred to the storage register when the strobe (STR) input is HIGH. Data in the storage register appears at the outputs whenever the output enable (OE) signal is HIGH.

Two serial outputs (QS1 and QS2) are available for cascading a number of CD4094B devices. Serial data is available at QS1 on positive-going clock edges to allow high-speed operation in cascaded systems with a fast clock rise time. The same serial data is available at QS2 on the next negative going clock edge. This is used for cascading CD4094B devices when the clock has a slow rise time.

It operates over a recommended V_{DD} power supply range of 3V to 15V referenced to V_{SS} (usually ground). Unused inputs must be connected to V_{DD} , V_{SS} , or another input.

Block Diagram

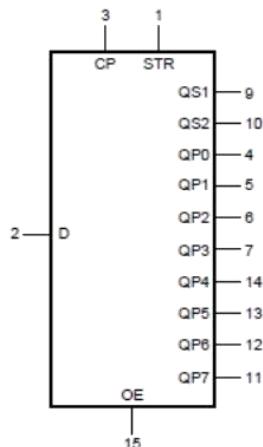


Figure 1. Logic symbol

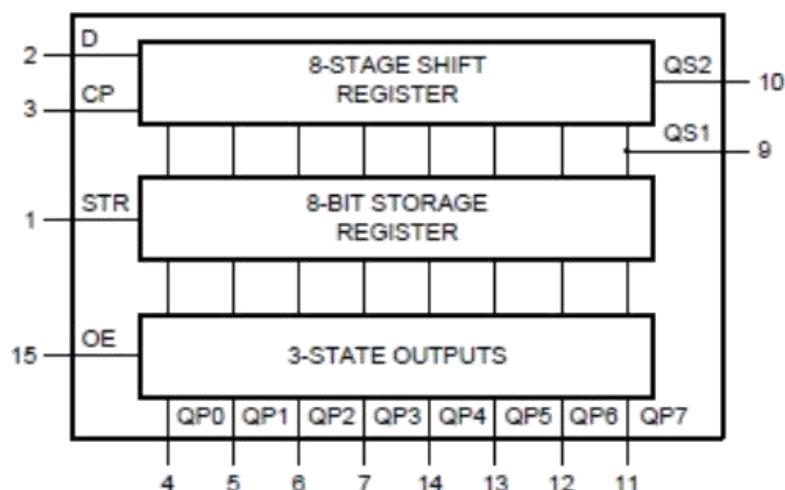


Figure 2. Functional diagram

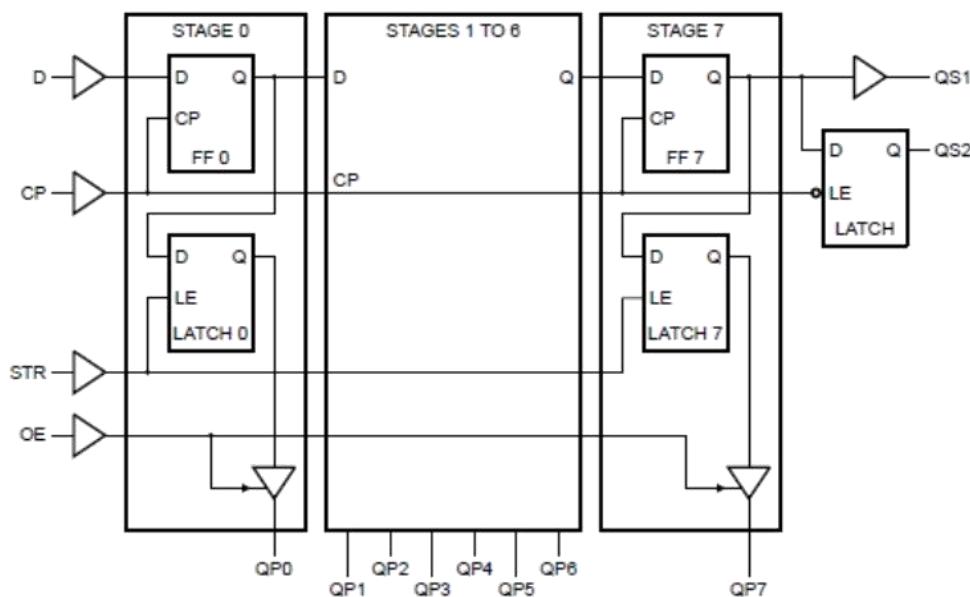


Figure 3. Logic diagram

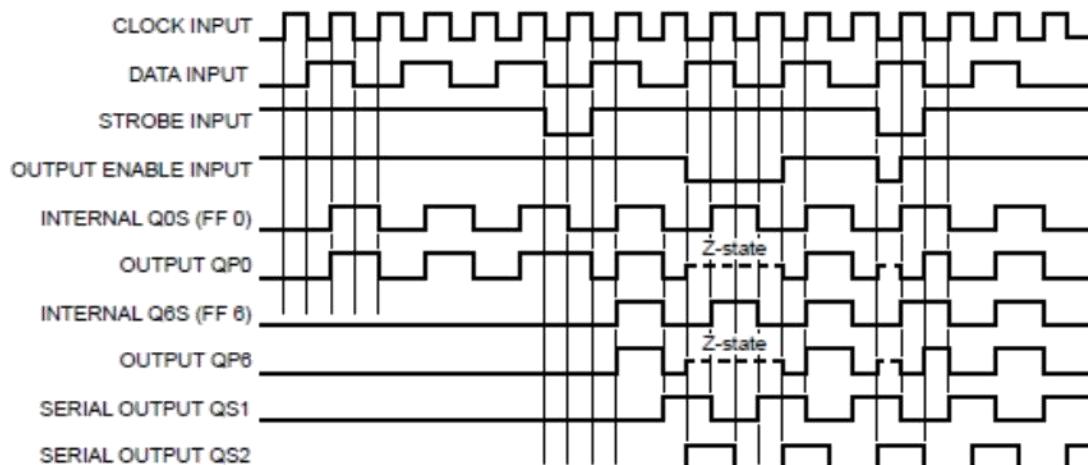


Figure 4. Timing diagram

Function Table

Input				Parallel output		Serial output	
CP	OE	STR	D	QP0	QPn	QS1	QS2
↑	L	X	X	Z	Z	Q6S	NC
↓	L	X	X	Z	Z	NC	Q7S
↑	H	L	X	NC	NC	Q6S	NC
↑	H	H	L	L	QPn-1	Q6S	NC
↑	H	H	H	H	QPn-1	Q6S	NC
↓	H	H	H	NC	NC	NC	Q7S

Note: H=HIGH voltage level; L=LOW voltage level; X=don't care; Z=HIGH-impedance OFF-state;

NC=no change; ↑=positive-going transition; ↓=negative-going transition;

Q6S=the data in register stage 6 before the LOW to HIGH clock transition;

Q7S=the data in register stage 7 before the HIGH to LOW clock transition.

Pin Configurations



DIP-16/SOP-16/TSSOP-16

Pin Description

Pin No.	Pin Name	Description
1	STR	strobe input
2	D	data input
3	CP	clock input
4	QP0	parallel output
5	QP1	parallel output
6	QP2	parallel output
7	QP3	parallel output
8	VSS	ground (0V)
9	QS1	serial output
10	QS2	serial output
11	QP7	parallel output
12	QP6	parallel output
13	QP5	parallel output
14	QP4	parallel output
15	OE	output enable input
16	VDD	supply voltage

Electrical Parameter

Absolute Maximum Ratings

(Voltages are referenced to VSS (ground=0V), unless otherwise specified.)

Parameter	Symbol	Conditions	Min.	Max.	Unit
supply voltage	V _{DD}	-	-0.5	+18	V
DC input current	I _{IK}	any one input	-	±10	mA
input voltage	V _I	all inputs	-0.5	V _{DD} +0.5	V
storage temperature	T _{stg}	-	-65	+150	°C
total power dissipation	P _{tot}	-	-	500	mW
device dissipation	P	per output transistor	-	100	mW
soldering temperature	T _L	10s	260		°C

Note: Stress greater than those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions outside those indicated in the operational sections of this specification are not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

Recommended Operating Conditions

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
supply voltage	V _{DD}	-	3	-	15	V
ambient temperature	T _{amb}	in free air	-40	-	+125	°C
data setup time	t _{su}	V _{DD} =5V	125	-	-	ns
		V _{DD} =10V	55	-	-	ns
		V _{DD} =15V	35	-	-	ns
clock pulse width	t _w	V _{DD} =5V	200	-	-	ns
		V _{DD} =10V	100	-	-	ns
		V _{DD} =15V	83	-	-	ns
clock input frequency	f _{max}	V _{DD} =5V		-	1.25	MHz
		V _{DD} =10V		-	2.5	MHz
		V _{DD} =15V		-	3	MHz
clock rise and fall time	t _{rCL} , t _{fCL}	V _{DD} =5V	-	-	15	us
		V _{DD} =10V	-	-	5	us
		V _{DD} =15V	-	-	5	us
strobe setup time	t _w	V _{DD} =5V	200	-	-	ns
		V _{DD} =10V	80	-	-	ns
		V _{DD} =15V	70	-	-	ns

Electrical Characteristics

DC Characteristics 1

($T_{amb}=25^{\circ}\text{C}$, voltages are referenced to V_{SS} (ground=0V), unless otherwise specified.)

Parameter	Symbol	Conditions (V)			Tamb=25°C			Unit
		V_o	V_{IN}	V_{DD}	Min.	Typ.	Max.	
supply current	I_{DD}	-	0, 5	5	-	-	5	uA
		-	0, 10	10	-	-	10	uA
		-	0, 15	15	-	-	20	uA
LOW-level output current	I_{OL}	0.4	0, 5	5	0.51	1	-	mA
		0.5	0, 10	10	1.3	2.6	-	mA
		1.5	0, 15	15	3.4	6.8	-	mA
HIGH-level output current	I_{OH}	4.6	0, 5	5	-0.51	-1	-	mA
		2.5	0, 5	5	-1.6	-3.2	-	mA
		9.5	0, 10	10	-1.3	-2.6	-	mA
		13.5	0, 15	15	-3.4	-6.8	-	mA
LOW-level output voltage	V_{OL}	-	0, 5	5	-	0	0.05	V
		-	0, 10	10	-	0	0.05	V
		-	0, 15	15	-	0	0.05	V
HIGH-level output voltage	V_{OH}	-	0, 5	5	4.95	5	-	V
		-	0, 10	10	9.95	10	-	V
		-	0, 15	15	14.95	15	-	V
LOW-level input voltage	V_{IL}	0.5, 4.5	-	5	-	-	1.5	V
		1, 9	-	10	-	-	3	V
		1.5, 13.5	-	15	-	-	4	V
HIGH-level input voltage	V_{IH}	0.5, 4.5	-	5	3.5	-	-	V
		1, 9	-	10	7	-	-	V
		1.5, 13.5	-	15	11	-	-	V
input leakage current	I_I	-	0, 15	15	-	-	± 1	uA
OFF-state output current	I_{OZ}	0, 15	0, 15	15	-	-	± 1	uA

DC Characteristics 2

($T_{amb} = -40^{\circ}\text{C}$ to $+85^{\circ}\text{C}$, voltages are referenced to V_{SS} (ground=0V), unless otherwise specified.)

Parameter	Symbol	Conditions (V)			$T_{amb} = -40^{\circ}\text{C}$		$T_{amb} = +85^{\circ}\text{C}$		Unit
		V_o	V_{IN}	V_{DD}	Min.	Max.	Min.	Max.	
supply current	I_{DD}	-	0, 5	5	-	5	-	150	uA
		-	0, 10	10	-	10	-	300	uA
		-	0, 15	15	-	20	-	600	uA
LOW-level output current	I_{OL}	0.4	0, 5	5	0.61	-	0.42	-	mA
		0.5	0, 10	10	1.5	-	1.1	-	mA
		1.5	0, 15	15	4	-	2.8	-	mA
HIGH-level output current	I_{OH}	4.6	0, 5	5	-0.61	-	-0.42	-	mA
		2.5	0, 5	5	-1.8	-	-1.3	-	mA
		9.5	0, 10	10	-1.5	-	-1.1	-	mA
		13.5	0, 15	15	-4	-	-2.8	-	mA
LOW-level output voltage	V_{OL}	-	0, 5	5	-	0.05	-	0.05	V
		-	0, 10	10	-	0.05	-	0.05	V
		-	0, 15	15	-	0.05	-	0.05	V
HIGH-level output voltage	V_{OH}	-	0, 5	5	4.95	-	4.95	-	V
		-	0, 10	10	9.95	-	9.95	-	V
		-	0, 15	15	14.95	-	14.95	-	V
LOW-level input voltage	V_{IL}	0.5, 4.5	-	5	-	1.5	-	1.5	V
		1, 9	-	10	-	3	-	3	V
		1.5, 13.5	-	15	-	4	-	4	V
HIGH-level input voltage	V_{IH}	0.5, 4.5	-	5	3.5	-	3.5	-	V
		1, 9	-	10	7	-	7	-	V
		1.5, 13.5	-	15	11	-	11	-	V
input leakage current	I_I	-	0, 15	15	-	± 1	-	± 1	uA
OFF-state output current	I_{OZ}	0, 15	0, 15	15	-	± 1	-	± 12	uA

DC Characteristics 3

($T_{amb}=-40^{\circ}\text{C}$ to $+125^{\circ}\text{C}$, voltages are referenced to V_{SS} (ground=0V), unless otherwise specified.)

Parameter	Symbol	Conditions (V)			$T_{amb}=-40^{\circ}\text{C}$		$T_{amb}=+125^{\circ}\text{C}$		Unit
		V_o	V_{IN}	V_{DD}	Min.	Max.	Min.	Max.	
supply current	I_{DD}	-	0, 5	5	-	5	-	150	uA
		-	0, 10	10	-	10	-	300	uA
		-	0, 15	15	-	20	-	600	uA
LOW-level output current	I_{OL}	0.4	0, 5	5	0.61	-	0.36	-	mA
		0.5	0, 10	10	1.5	-	0.9	-	mA
		1.5	0, 15	15	4	-	2.4	-	mA
HIGH-level output current	I_{OH}	4.6	0, 5	5	-0.61	-	-0.36	-	mA
		2.5	0, 5	5	-1.8	-	-1.15	-	mA
		9.5	0, 10	10	-1.5	-	-0.9	-	mA
		13.5	0, 15	15	-4	-	-2.4	-	mA
LOW-level output voltage	V_{OL}	-	0, 5	5	-	0.05	-	0.05	V
		-	0, 10	10	-	0.05	-	0.05	V
		-	0, 15	15	-	0.05	-	0.05	V
HIGH-level output voltage	V_{OH}	-	0, 5	5	4.95	-	4.95	-	V
		-	0, 10	10	9.95	-	9.95	-	V
		-	0, 15	15	14.95	-	14.95	-	V
LOW-level input voltage	V_{IL}	0.5, 4.5	-	5	-	1.5	-	1.5	V
		1, 9	-	10	-	3	-	3	V
		1.5, 13.5	-	15	-	4	-	4	V
HIGH-level input voltage	V_{IH}	0.5, 4.5	-	5	3.5	-	3.5	-	V
		1, 9	-	10	7	-	7	-	V
		1.5, 13.5	-	15	11	-	11	-	V
input leakage current	I_I	-	0, 15	15	-	± 1	-	± 1	uA
OFF-state output current	I_{OZ}	0, 15	0, 15	15	-	± 1	-	± 12	uA

AC Characteristics

($T_{amb}=25^{\circ}C$, $V_{SS}=0V$, $t_r = t_f = 20\text{ns}$, $C_L = 50\text{pF}$, $R_L = 200\text{k}\Omega$, unless otherwise specified.)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit	
propagation delay time	t_{PHL}, t_{PLH}	CP to QS1; see Figure 6	$V_{DD}=5V$	-	300	600	ns
			$V_{DD}=10V$	-	125	250	ns
			$V_{DD}=15V$	-	95	190	ns
		CP to QS2; see Figure 6	$V_{DD}=5V$	-	230	460	ns
			$V_{DD}=10V$	-	110	220	ns
			$V_{DD}=15V$	-	75	150	ns
		CP to QPn; see Figure 6	$V_{DD}=5V$	-	420	840	ns
			$V_{DD}=10V$	-	195	390	ns
			$V_{DD}=15V$	-	135	270	ns
		STR to QPn; see Figure 7	$V_{DD}=5V$	-	290	580	ns
			$V_{DD}=10V$	-	145	290	ns
			$V_{DD}=15V$	-	100	200	ns
HIGH to OFF-state/ OFF-state to HIGH propagation delay	t_{PHZ}, t_{PZH}	OE to QPn; see Figure 8	$V_{DD}=5V$	-	140	280	ns
			$V_{DD}=10V$	-	60	120	ns
			$V_{DD}=15V$	-	45	90	ns
LOW to OFF-state/OFF -state to LOW propagation delay	t_{PLZ}, t_{PZL}	OE to QPn; see Figure 8	$V_{DD}=5V$	-	100	200	ns
			$V_{DD}=10V$	-	50	100	ns
			$V_{DD}=15V$	-	40	80	ns
pulse width	t_w	minimum HIGH strobe pulse; see Figure 7	$V_{DD}=5V$	-	100	200	ns
			$V_{DD}=10V$	-	40	80	ns
			$V_{DD}=15V$	-	35	70	ns
		minimum LOW clock pulse; see Figure 6	$V_{DD}=5V$	-	100	200	ns
			$V_{DD}=10V$	-	50	100	ns
			$V_{DD}=15V$	-	40	83	ns
data setup time	t_{su}	D to CP; see Figure 9	$V_{DD}=5V$	-	60	125	ns
			$V_{DD}=10V$	-	30	55	ns
			$V_{DD}=15V$	-	20	35	ns
transition time	t_t	-	$V_{DD}=5V$	-	100	200	ns
			$V_{DD}=10V$	-	50	100	ns
			$V_{DD}=15V$	-	40	80	ns
clock input rise and fall time	t_{fCL}, t_{fCL}	-	$V_{DD}=5V$	15	-	-	us
			$V_{DD}=10V$	5	-	-	us
			$V_{DD}=15V$	5	-	-	us
maximum clock frequency	f_{max}	see Figure 6	$V_{DD}=5V$	1.25	2.5	-	MHz
			$V_{DD}=10V$	2.5	5	-	MHz
			$V_{DD}=15V$	3	6	-	MHz
input capacitance	C_I	any input	-	5	7.5	pF	

Note: t_t is the same as t_{TLH} and t_{THL} .

Testing Circuit

AC Testing Circuit

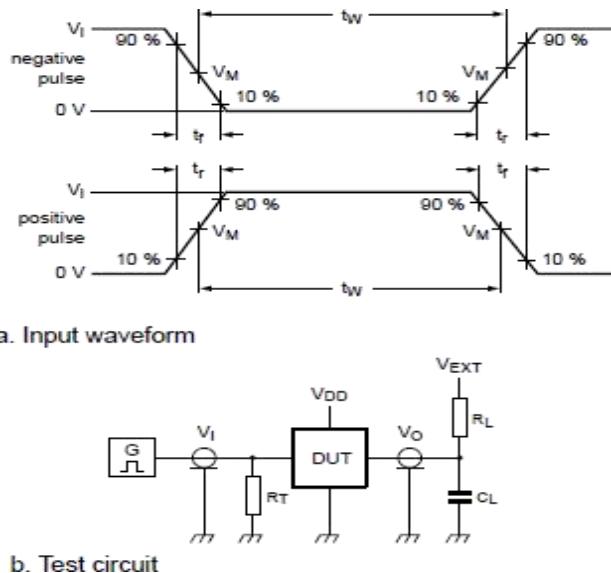


Figure 5. Test circuit for switching times

Definitions for test circuit:

DUT=Device Under Test.

C_L =Load capacitance including jig and probe capacitance.

R_T =Termination resistance should be equal to the output impedance Z_o of the pulse generator.

R_L =Load resistance.

V_{EXT} =External voltage for measuring switching times.

AC Testing Waveforms

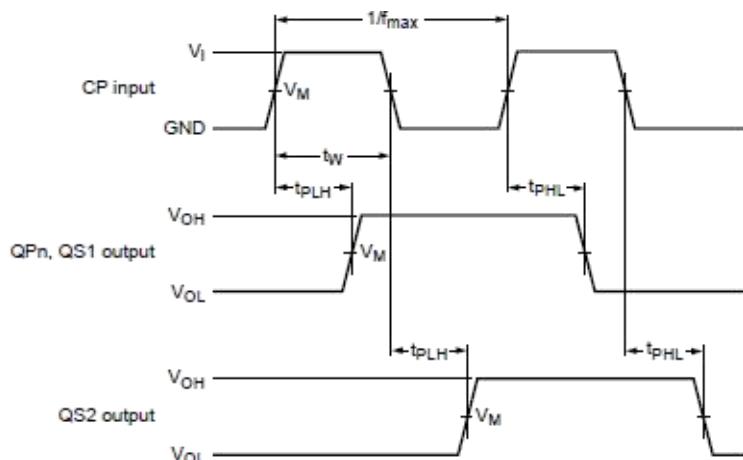


Figure 6. Clock to outputs propagation delays, and clock pulse width and maximum frequency

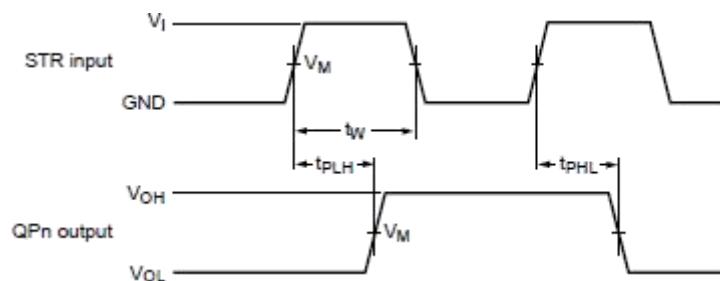


Figure 7. Strobe to output propagation delays, and strobe pulse width, set up and hold times

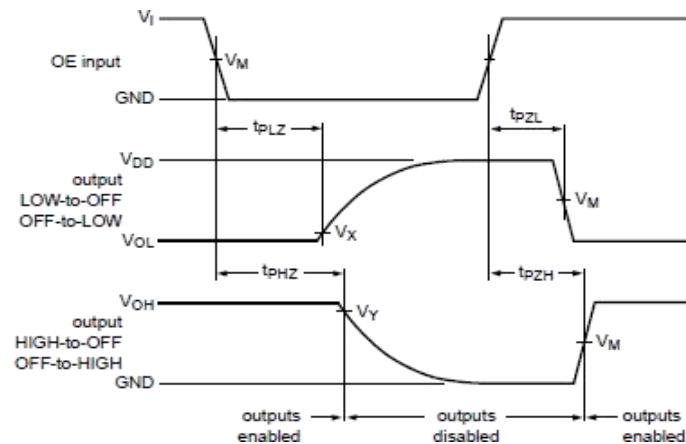


Figure 8. 3-state output enable and disable times for OE input

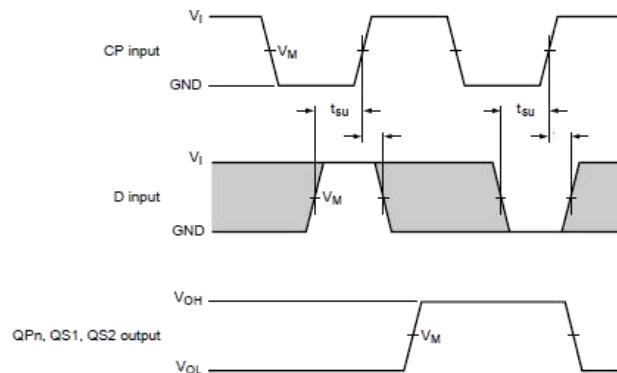


Figure 9. Data input data set up and hold times

Measurement Points

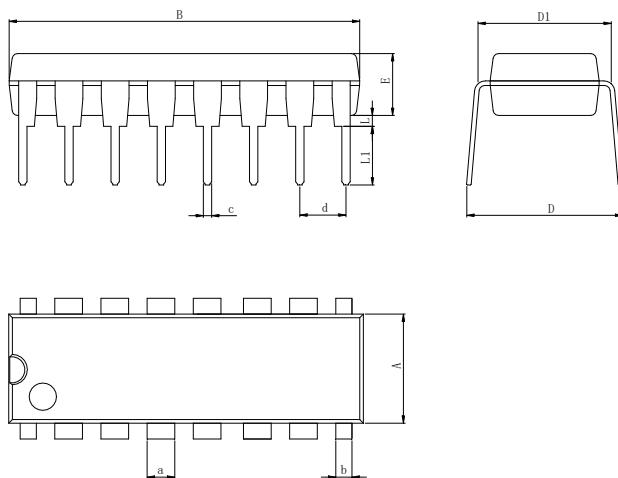
Supply voltage	Input		Output		
V_{DD}	V_M	V_M	V_X	V_Y	
5V to 15V	$0.5 \times V_{DD}$	$0.5 \times V_{DD}$	$0.1 \times V_{DD}$	$0.9 \times V_{DD}$	

Test Data

Supply voltage	Input		Load		Output		
V_{DD}	V_I	t_r, t_f	C_L	R_L	t_{PHL}, t_{PLH}	t_{PHZ}, t_{PZH}	t_{PLZ}, t_{PZL}
5V to 15V	V_{SS} or V_{DD}	$\leq 20\text{ns}$	50pF	1k Ω	open	V_{SS}	V_{DD}

Physical Dimensions

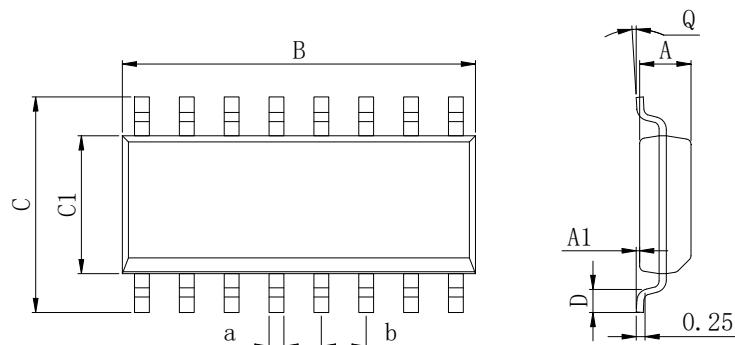
DIP-16



Dimensions In Millimeters(DIP-16)

Symbol:	A	B	D	D1	E	L	L1	a	b	c	d
Min:	6.10	18.94	8.10	7.42	3.10	0.50	3.00	1.50	0.85	0.40	2.54 BSC
Max:	6.68	19.56	10.9	7.82	3.55	0.70	3.60	1.55	0.90	0.50	

SOP-16

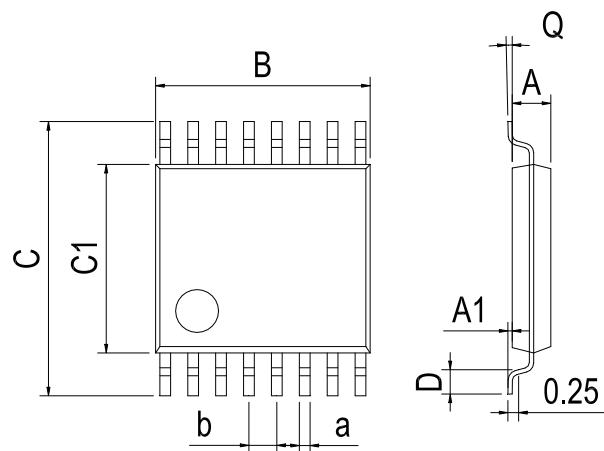


Dimensions In Millimeters(SOP-16)

Symbol:	A	A1	B	C	C1	D	Q	a	b
Min:	1.35	0.05	9.80	5.80	3.80	0.40	0°	0.35	1.27 BSC
Max:	1.55	0.20	10.0	6.20	4.00	0.80	8°	0.45	

Physical Dimensions

TSSOP-16



Dimensions In Millimeters(TSSOP-16)									
Symbol:	A	A1	B	C	C1	D	Q	a	b
Min:	0.85	0.05	4.90	6.20	4.30	0.40	0°	0.20	0.65 BSC
Max:	0.95	0.20	5.10	6.60	4.50	0.80	8°	0.25	

Revision History

REVISION NUMBER	DATE	REVISION	PAGE
V1.0	2014-11	New	1-15
V1.1	2021-4	Modify the package dimension diagram TSSOP-16	13
V1.2	2024-12	Document Reformatting	

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